

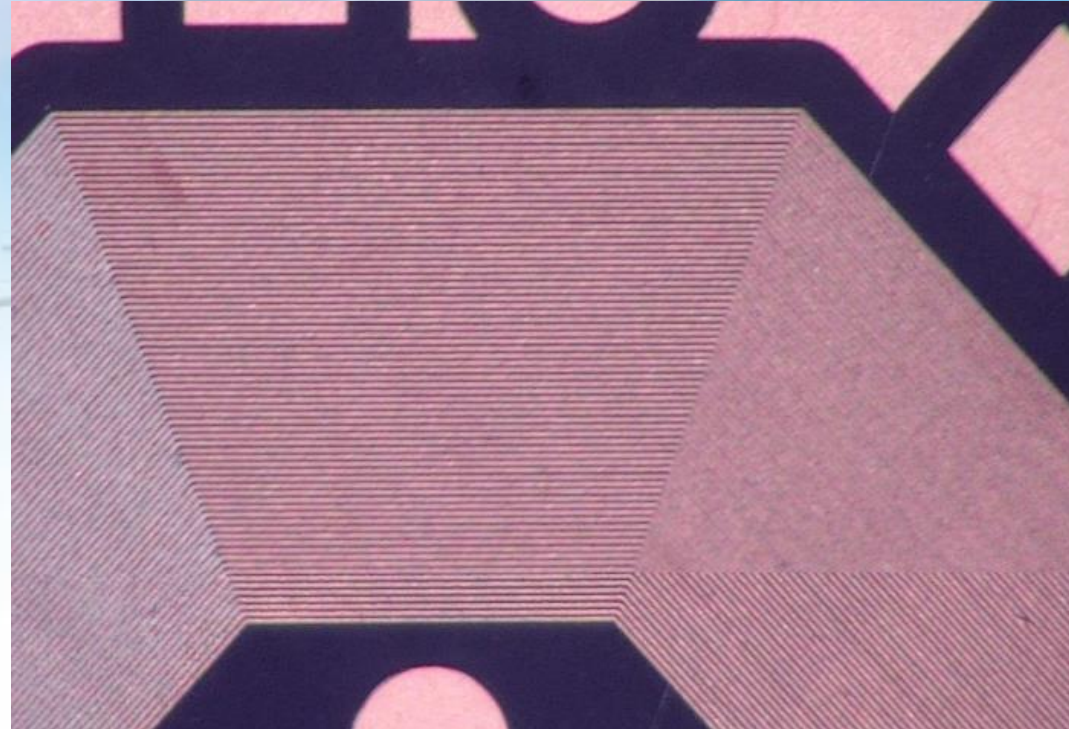
Partners In Performance



FTG Corporation
FTG:TSX



Averatek A-SAP™ Process

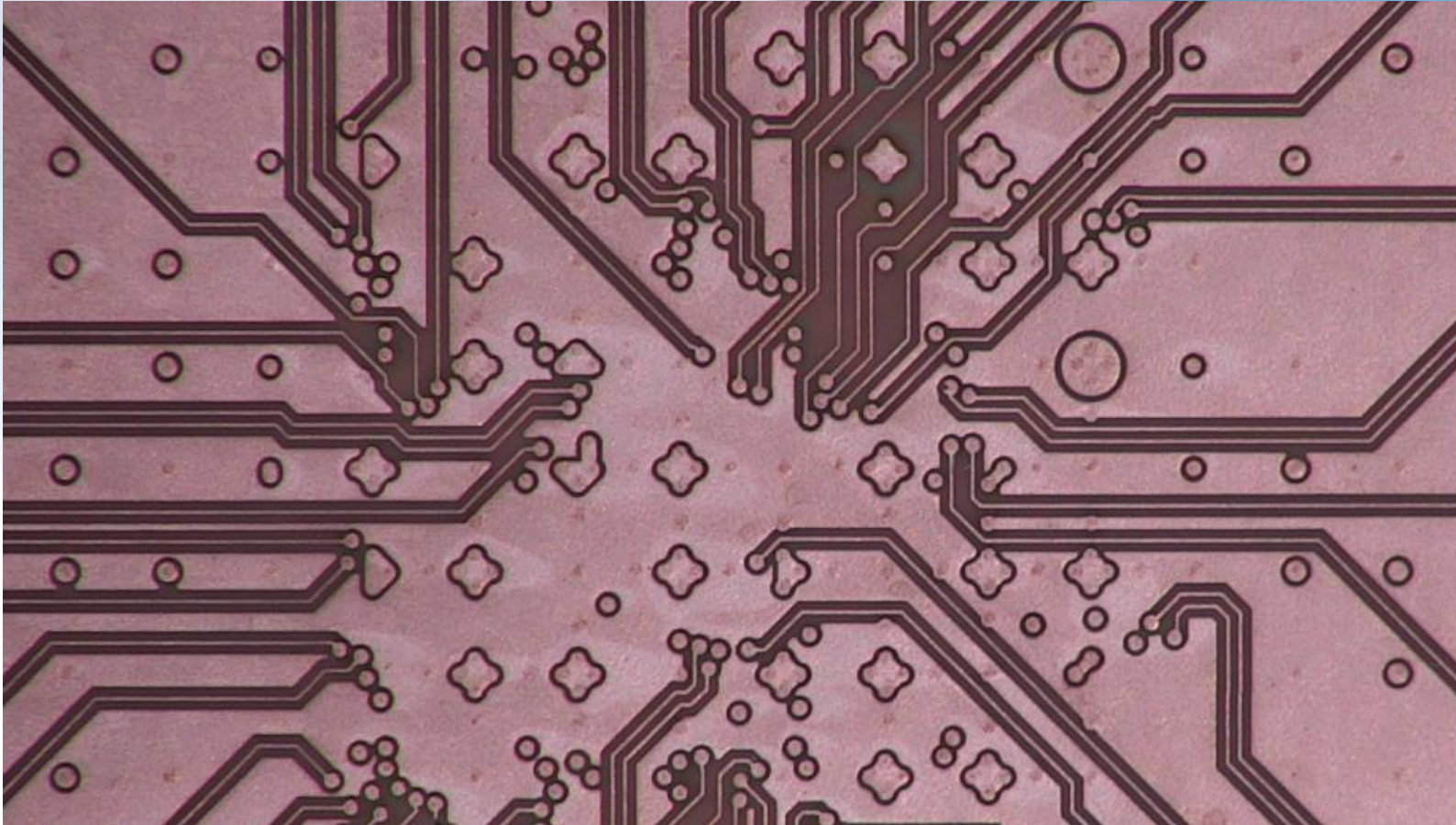


25 μ m (0.001") Line Width and Spacing after Plating
Copper Thickness 20.8 μ m (0.00082")



Averatek A-SAP™ Process

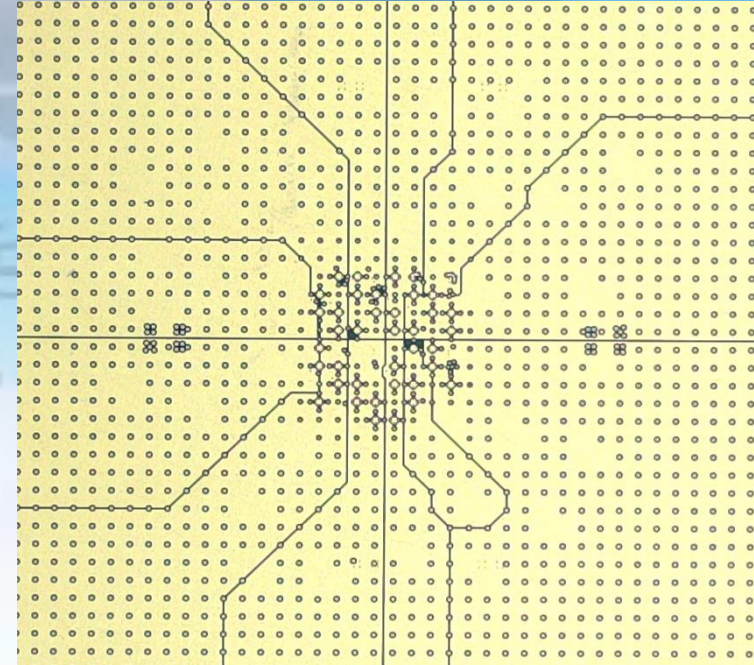
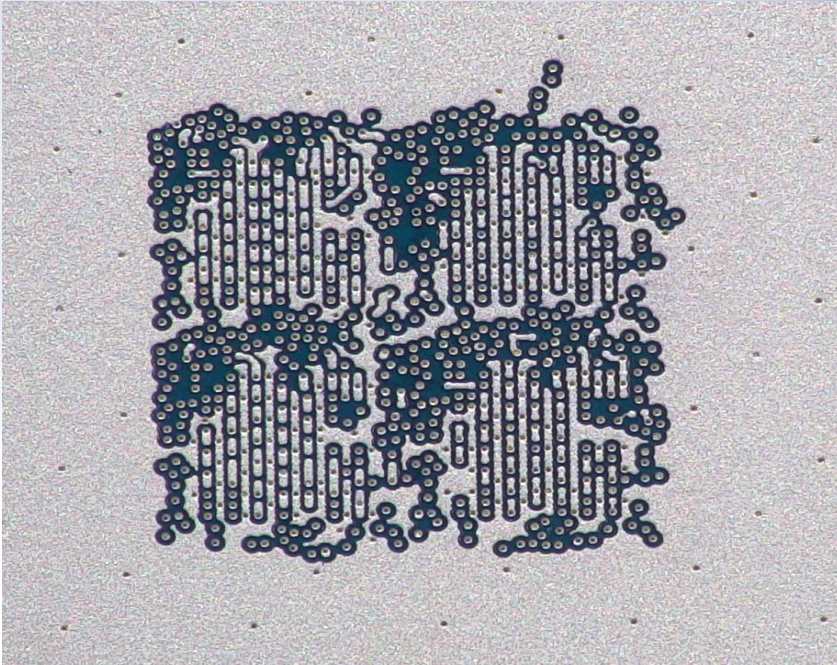
Operational
Excellence



“25 μm (0.001”) Line Width, 50 μm (0.002”) Spacing after Plating and Etching – Copper Thickness 23.6 μm (0.00093”)



Averatek A-SAP™ Process 6 layer Build Up Design



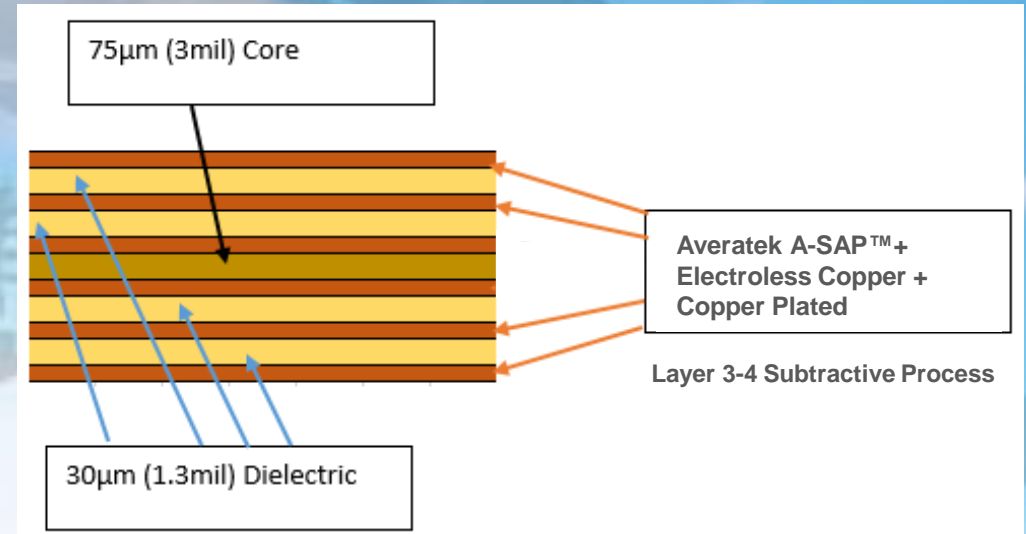
25 μ m (0.001") Line Width, 50 μ m (0.002") Spacing after
Plating and
Etching – Copper Thickness 23.6 μ m (0.00093")



Reliability – Coupon Design



- A 6 layers - 400 μ m (16mil) thick 'D' coupon using build up technology.
- Material: Panasonic R1755V/R1650V
- Design was a build up technology using 100 μ m (4mil) microvias (0.33 to 1 aspect ratio)
- Only internal Microvias were copper plated shut.
- Surface finish- ENIG

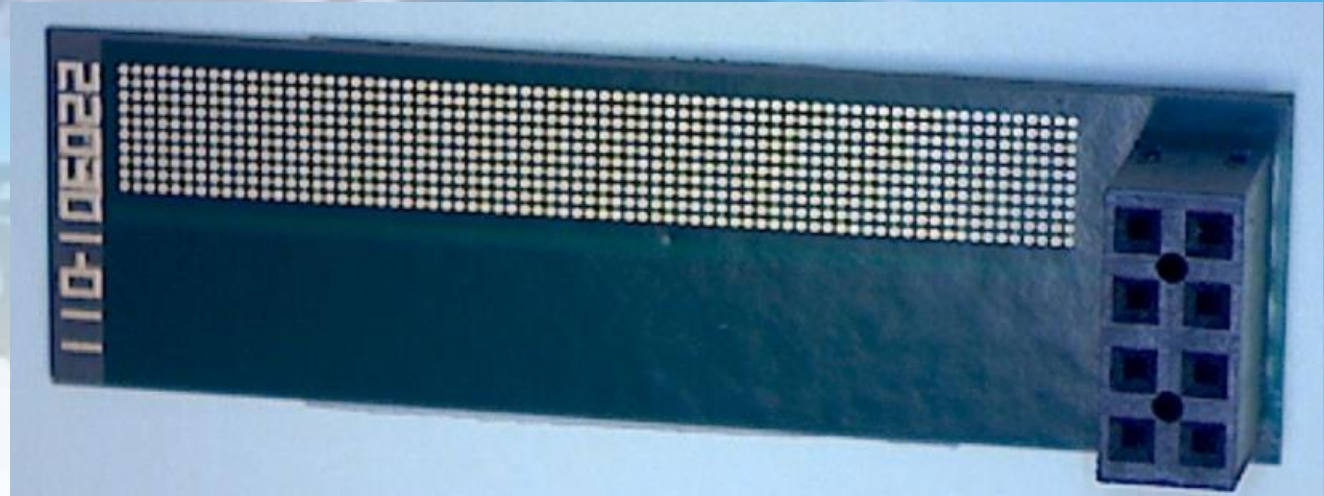




Thermal Stress Testing

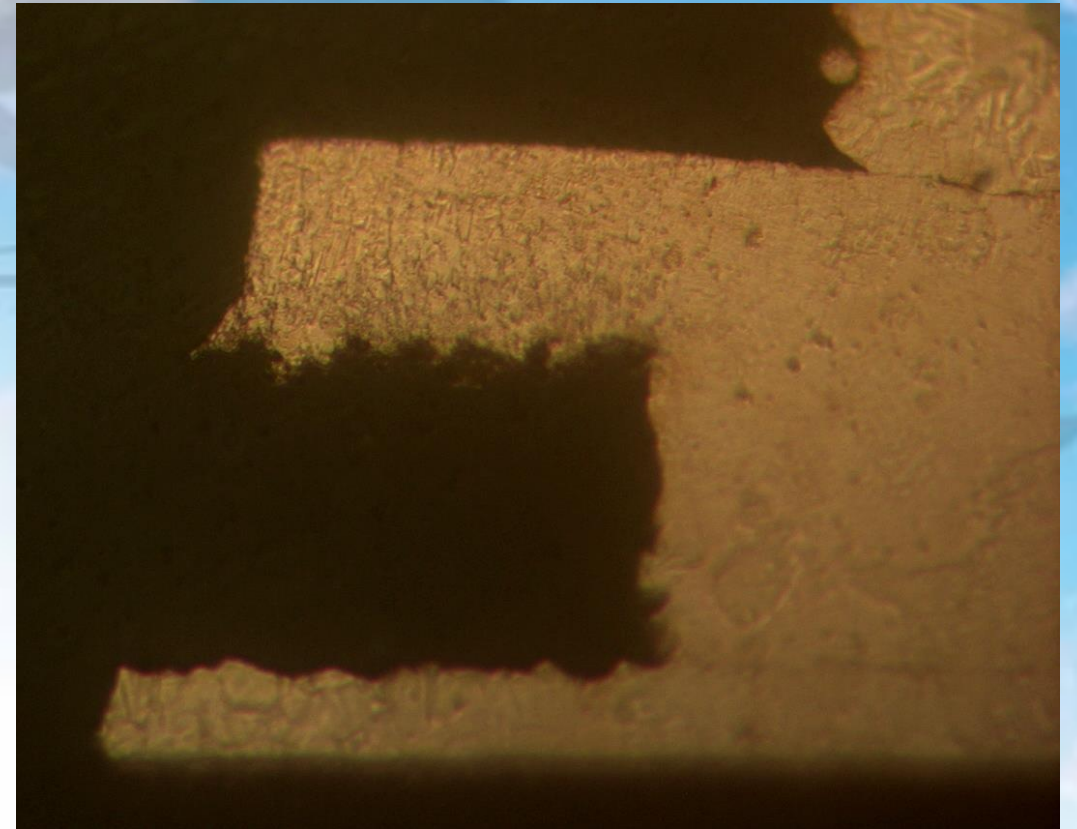
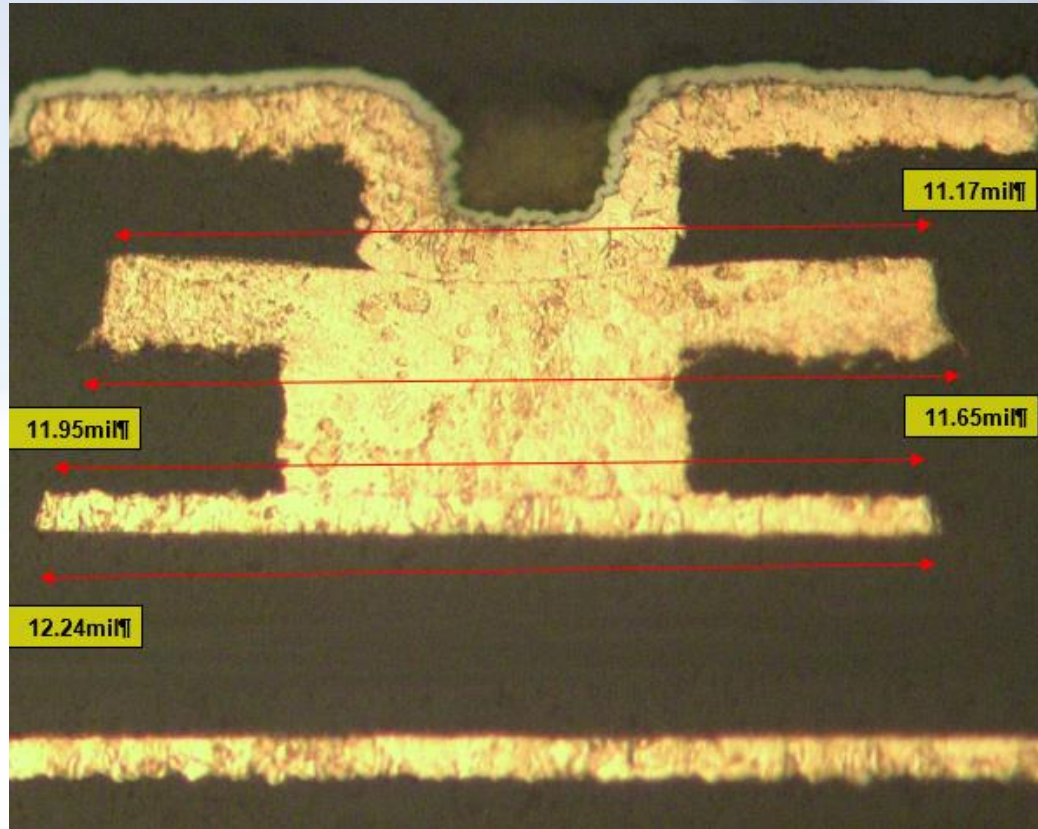


- Coupons were sent to CAT Inc. for Om testing
- Test Parameters:
 - 6X Reflow @ 265⁰ C
 - Thermal Shock – 100 Cycles @ (-)45⁰ – 150⁰ C
- Acceptance criteria – Change in resistance <5%
- No visual delamination



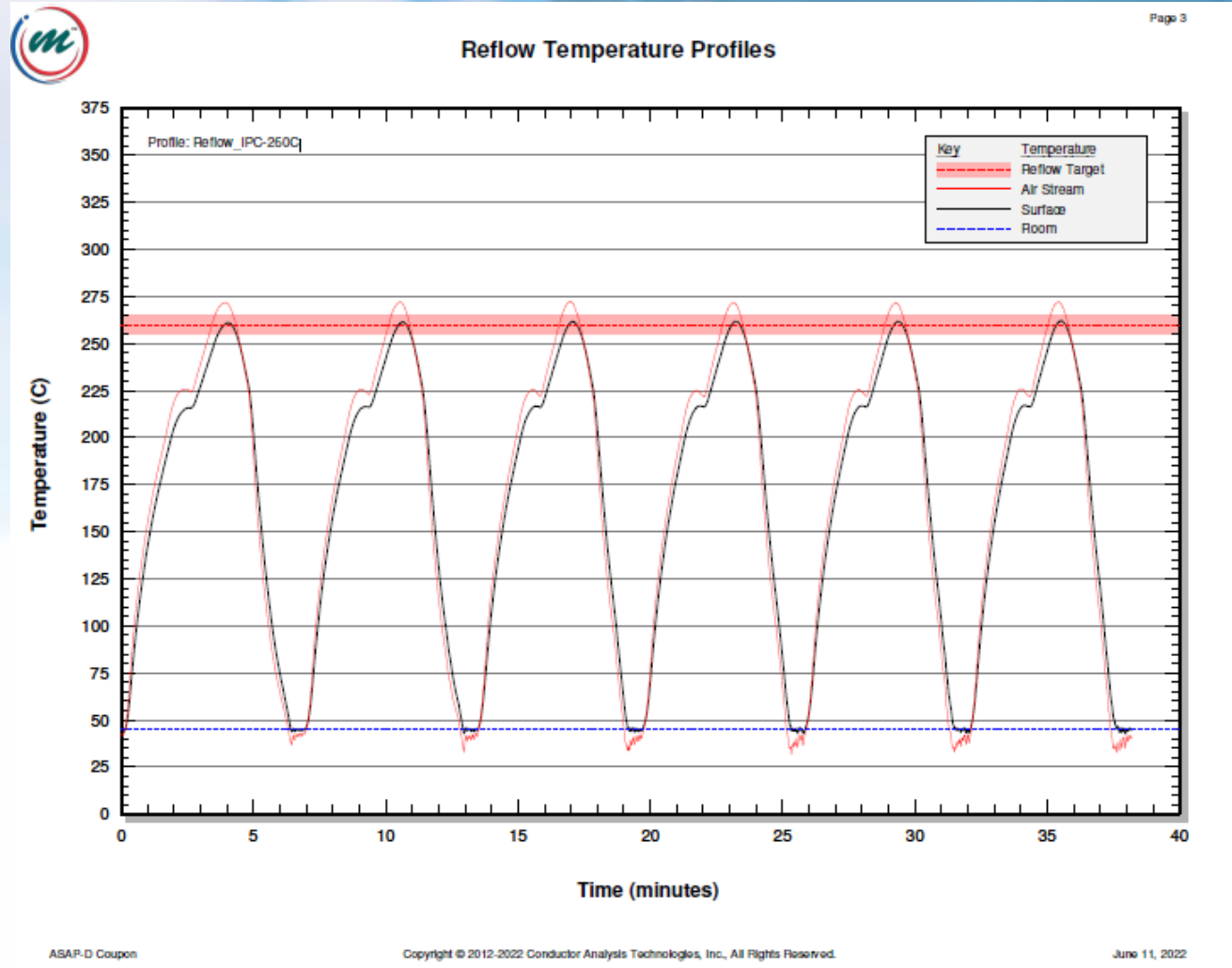


Averatek A-SAP™ Etch Capability





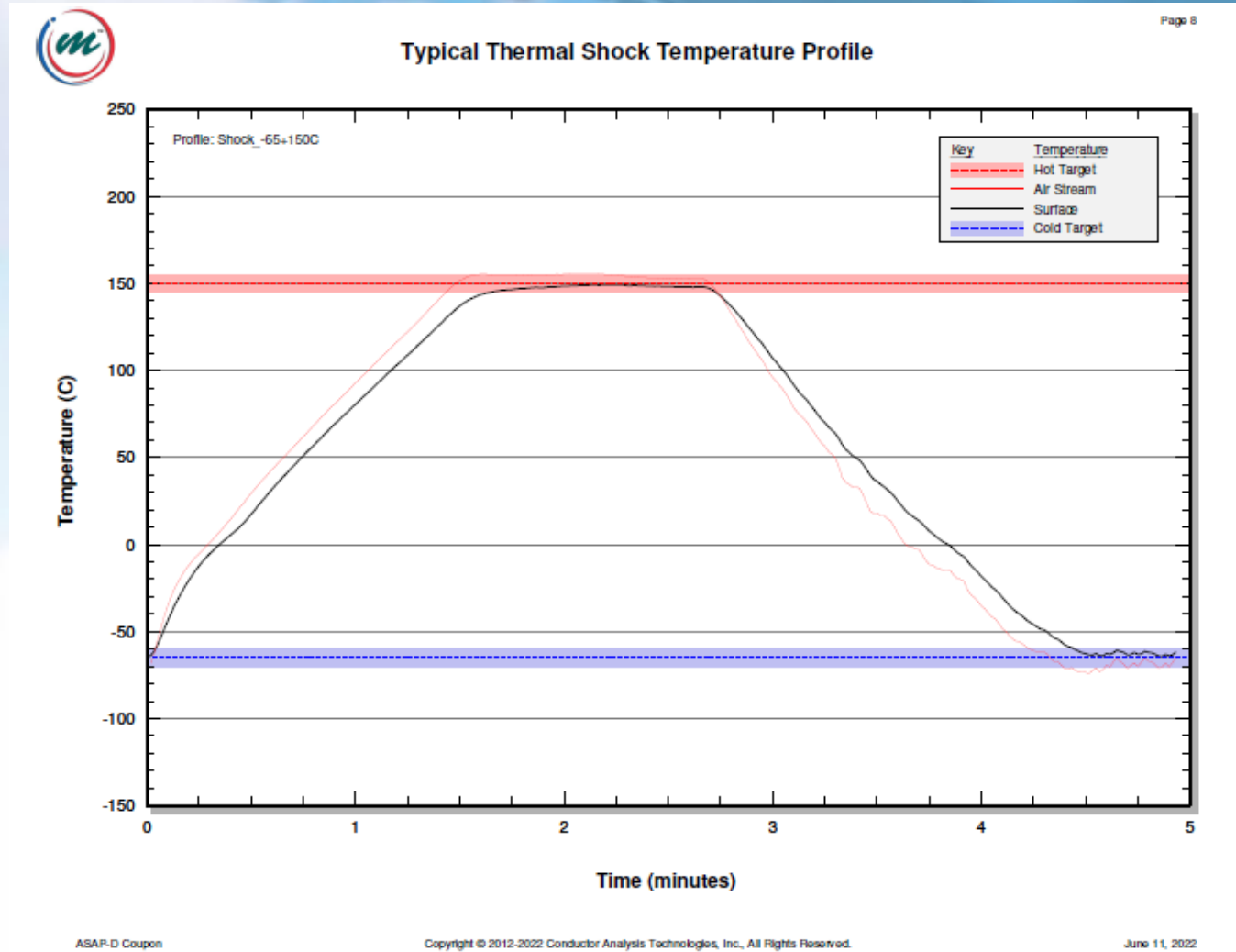
Thermal Stress Testing



Pre-conditioning – Reflow 6X @265°C



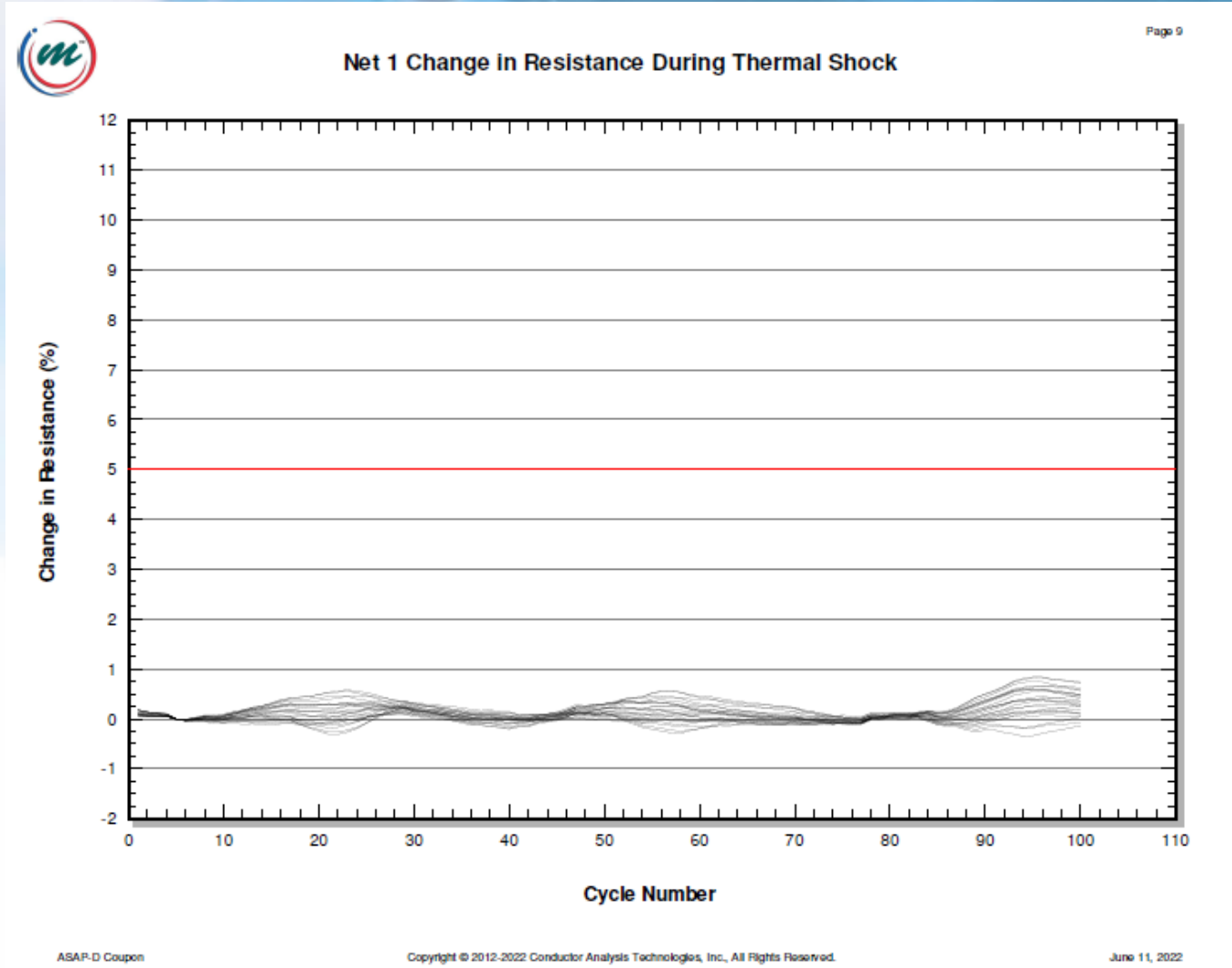
Thermal Stress Testing



Thermal Shock Profile



Thermal Stress Testing



ASAP-D Coupon

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June 11, 2022

Change in Resistance during Thermal Shock